

**Signal Integrity Issues
for Reliable Electronic System Designs**

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Outline

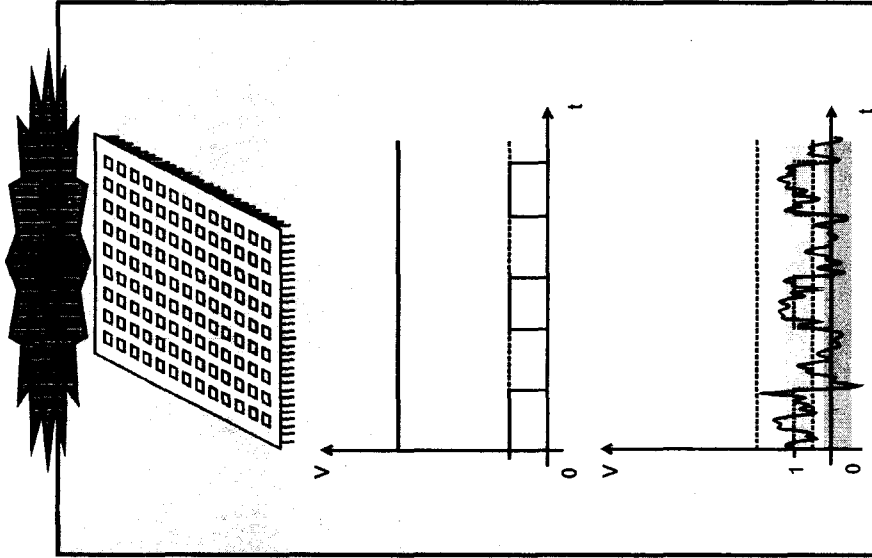
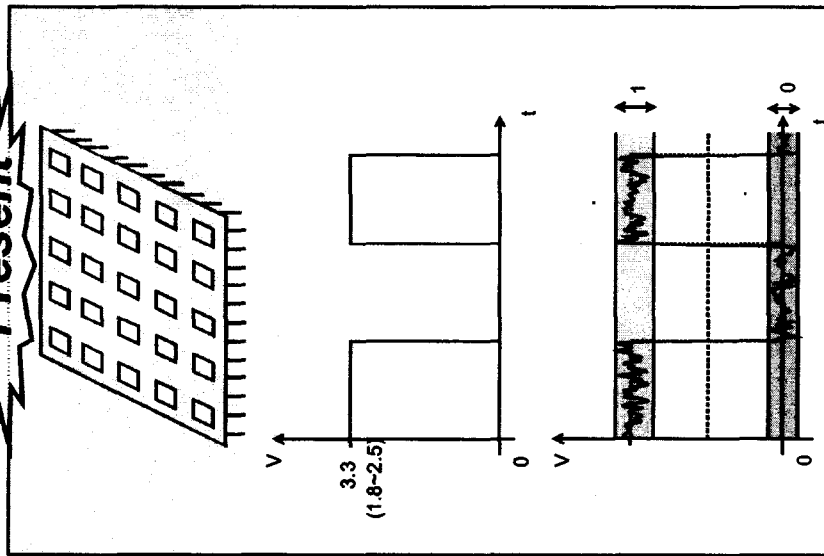
- **General Introduction**
- **Signal Integrity Issues for Electronic System Designs**
- **Estimation-Based System Design**
 - **Related Issues**
 - **Summary and Conclusion**

▲ **It was “Reliability Analysis”**

But It is “Reliable Design” !!!

Future Disaster: Technical Challenges

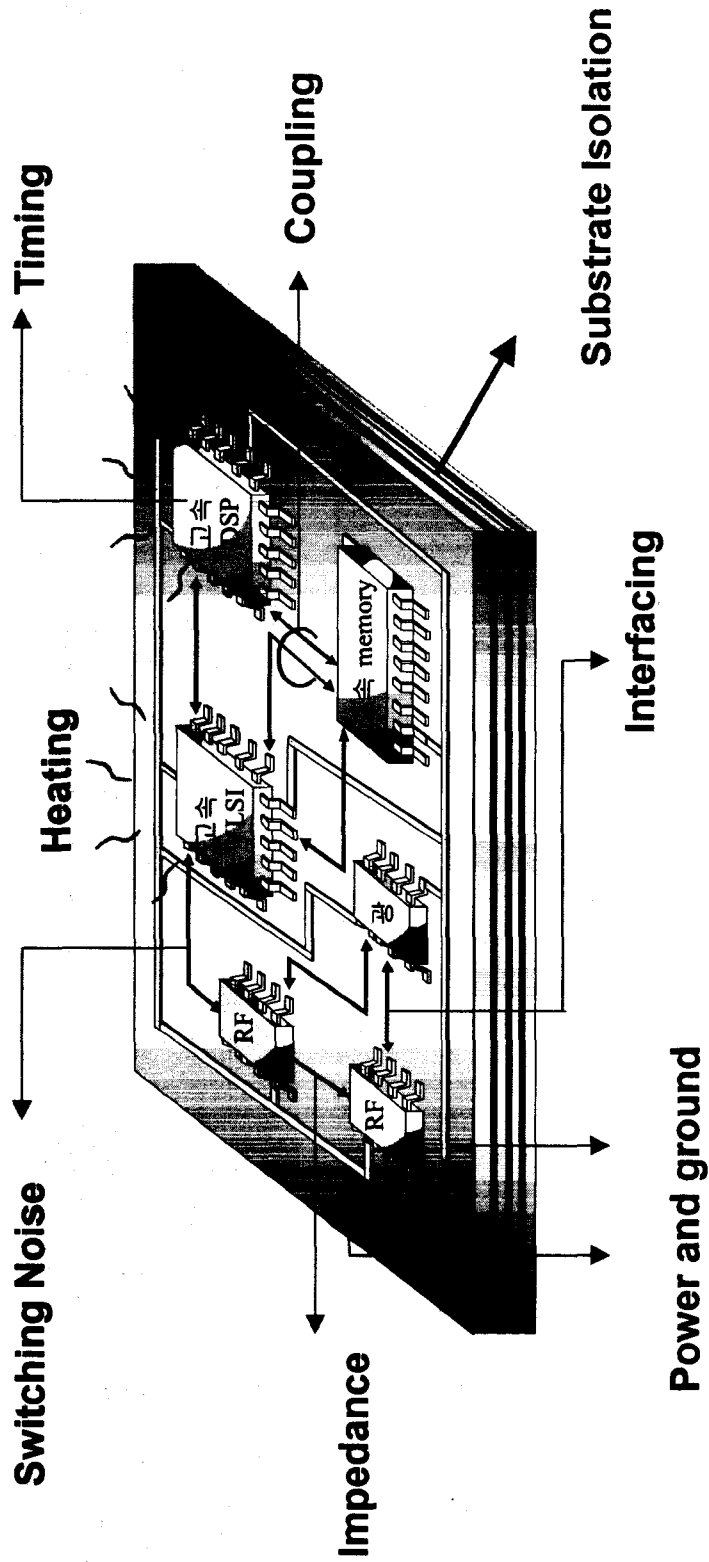
Present



How is it going to be ?

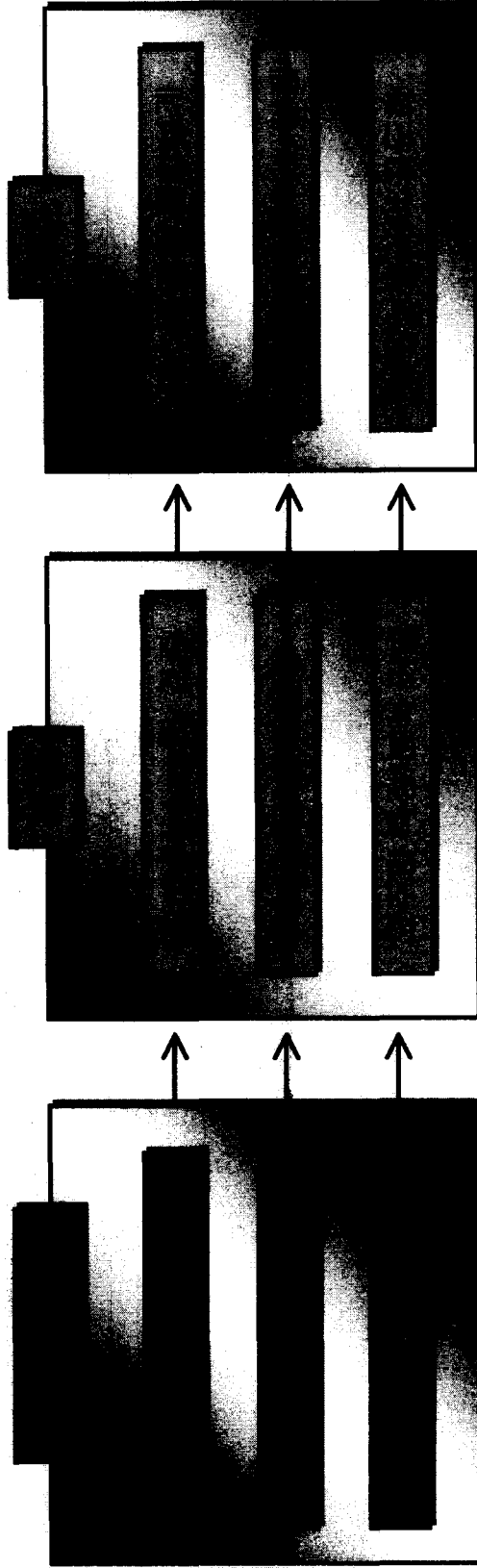
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Why ?



▶ **Key Issue is the Signal Integrity Verification of the System !!**

Everybody Knows it, But ...??



Goal: System Level Integration Tech. Development !!

Where Are You ?

There is One Group of Engineers who believe

- **CAD Tools are Everything !!**
- **Theory is One Thing, Design is Another !!**

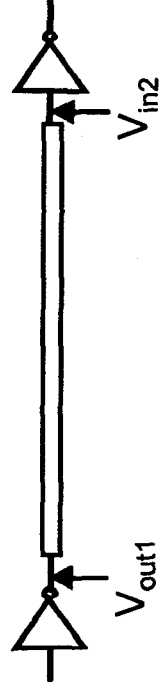
There is Another Group of Engineers who believe

- **Engineers are More Important than CAD Tools !!**
- **Design is the Simplified Version of a Theory !!**

▲ Detailed Problems

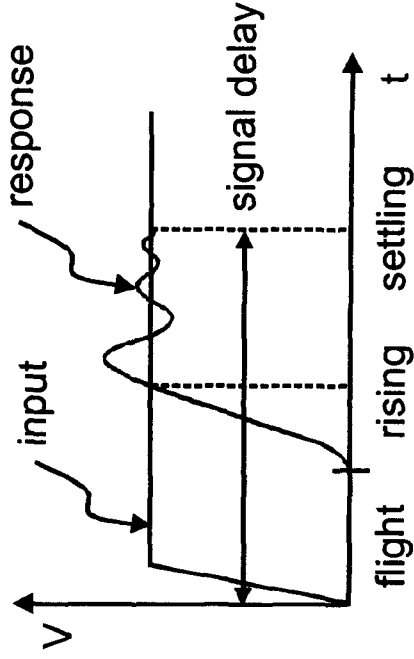
1. Timing Problem: Digital Signal Delay

- Signal Delay



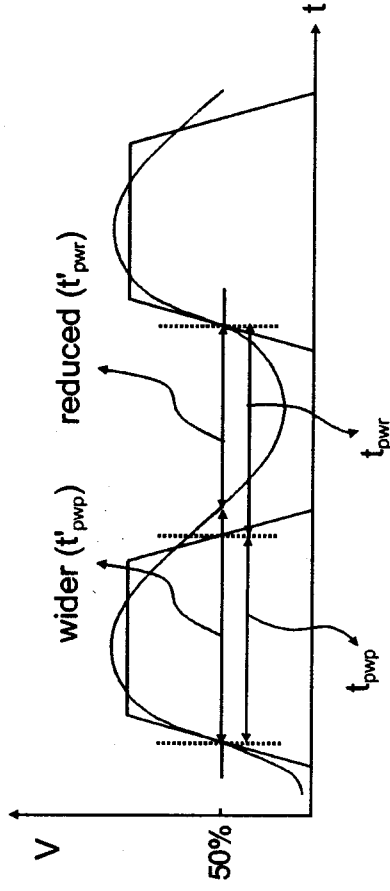
➔ for ideal system $V_{out1} = V_{in2}$

- Schematic Presentation of Delay

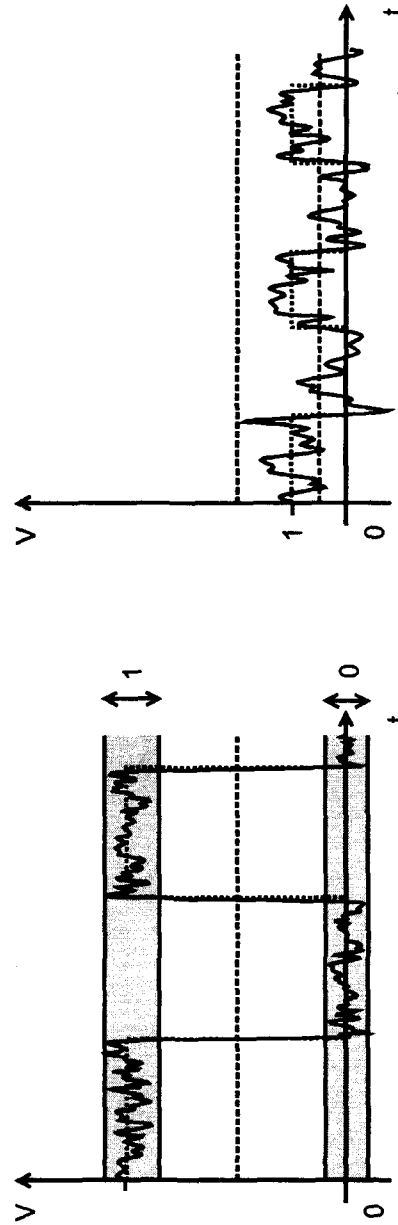
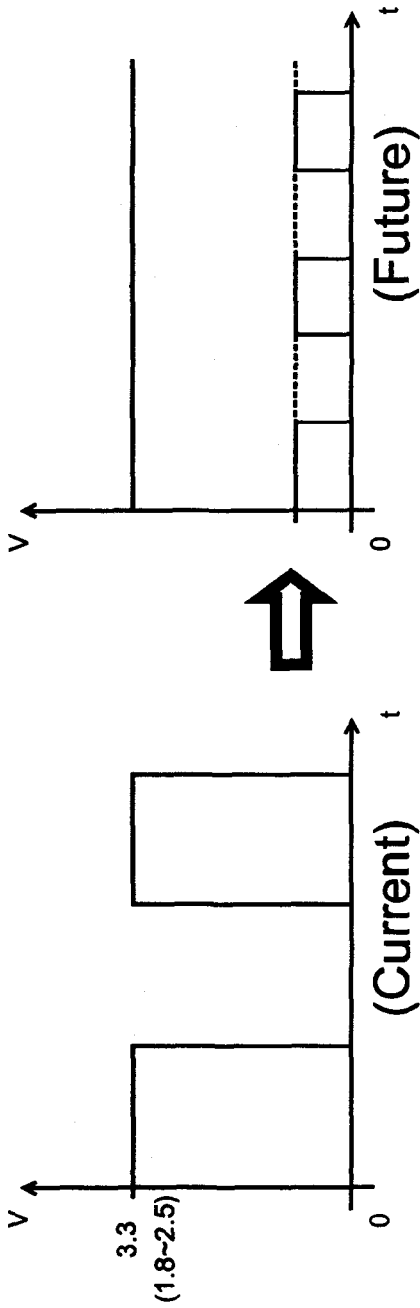


2. Dispersion

- Pulse Spreading



3. Little Noise Margin



Problem

No Problem

4. Electromagnetic Coupling: Crosstalk

High Potential Line (Ansan)



(Seminar Room)



(Lobby)

High Potential Line (Suwon)



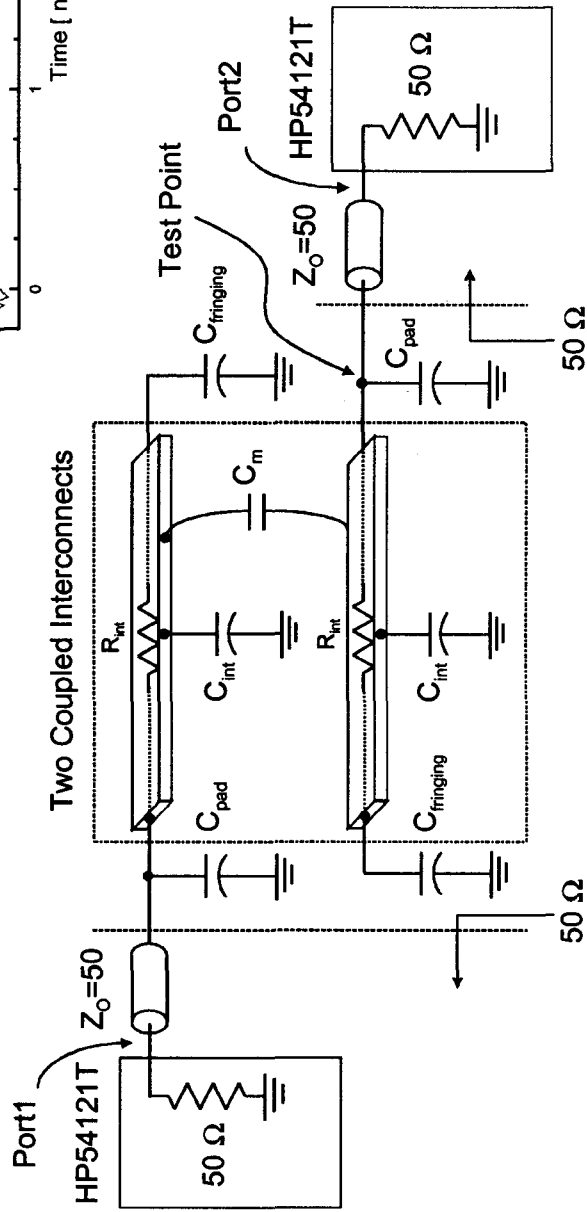
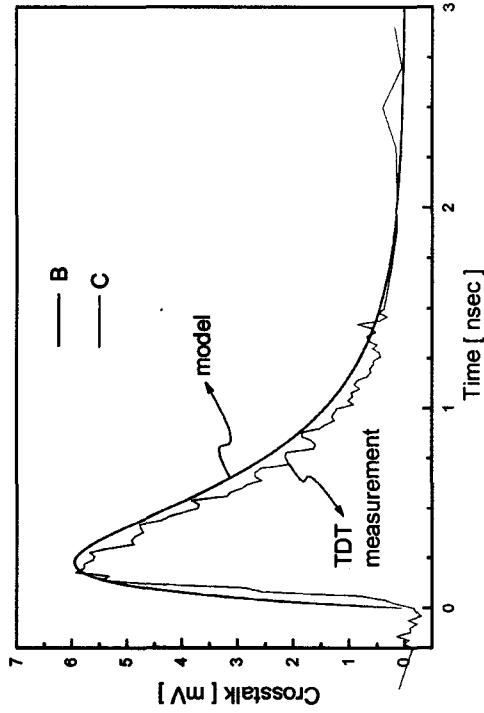
Safe

Die

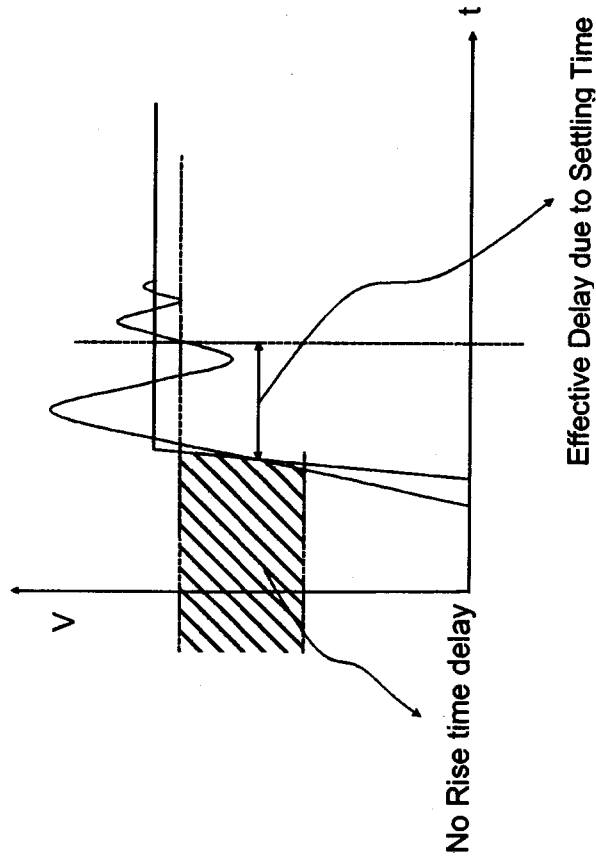
Why?

Crosstalk/Signal-Coupling

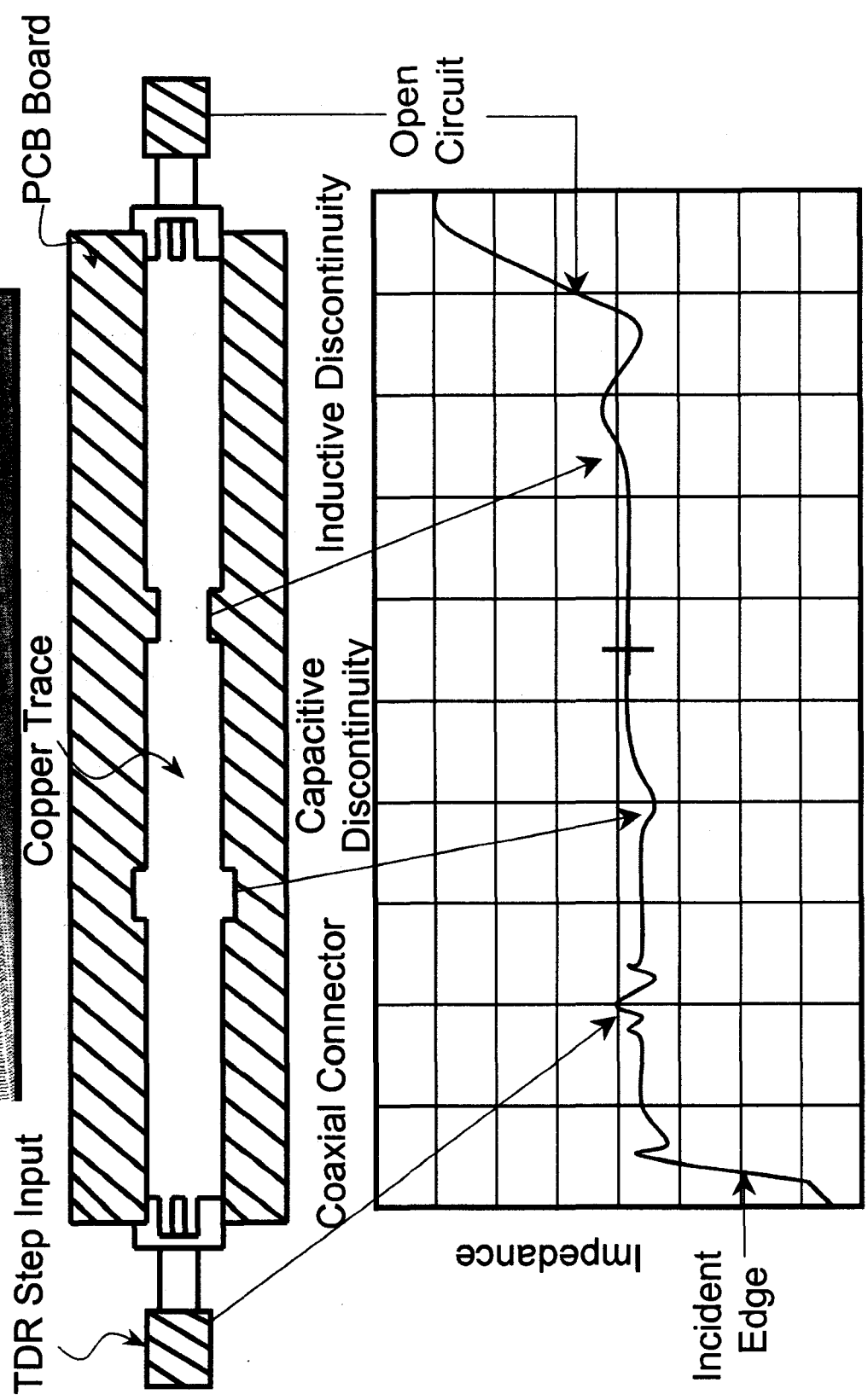
- Why Crosstalk ?
- Aspect Ratio increase
- Red. Spacing between the lines
- Inductive Coupling



5. Reflection : Cause significant settling time

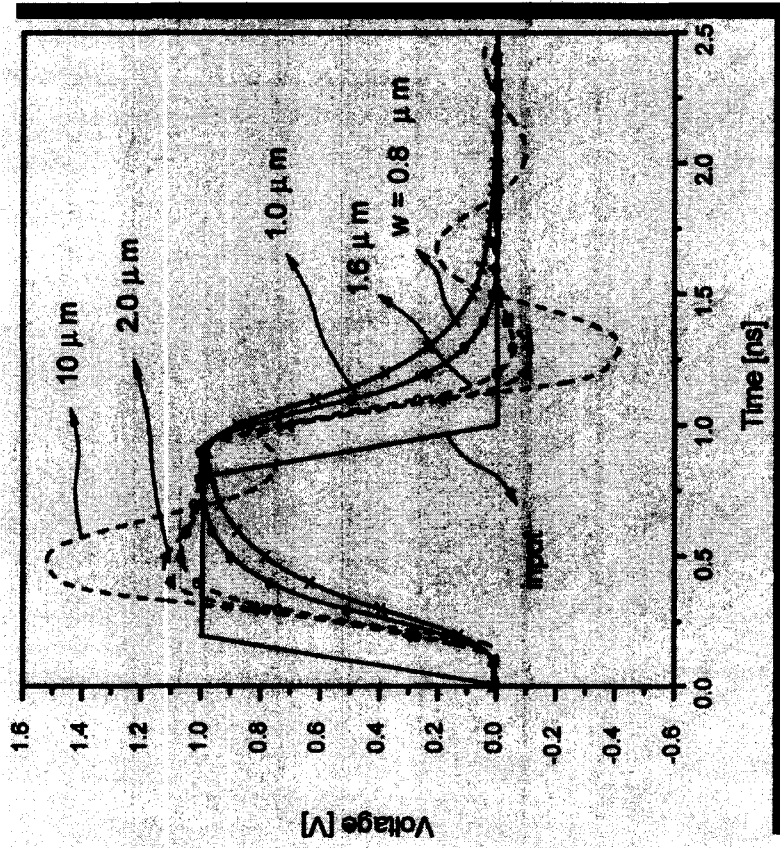


IMPEDANCE MISMATCHES IN COAXIAL CABLES



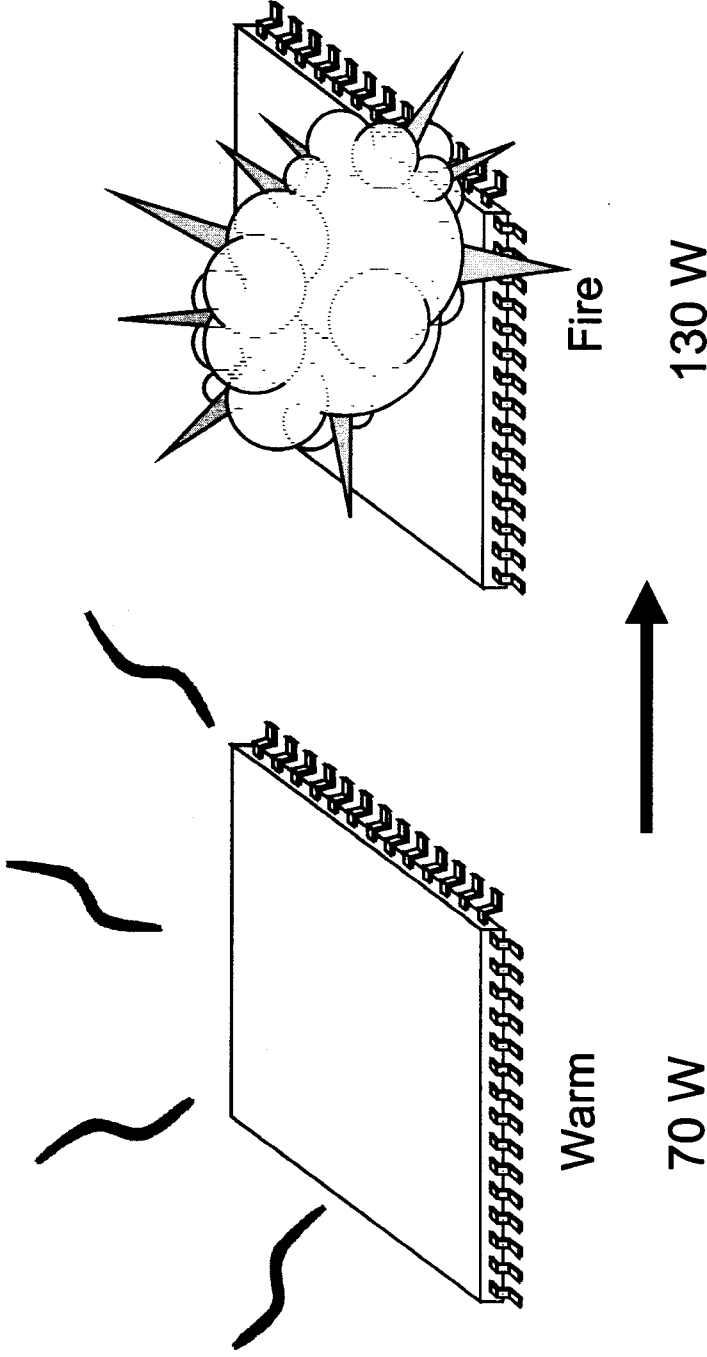
Time (Or Distance) — Prof. Yungseon Eo

- continued -



Responses for a pulse of the $t_r = 0.2$ ns with different line widths

6. Thermal Problem due to High Power

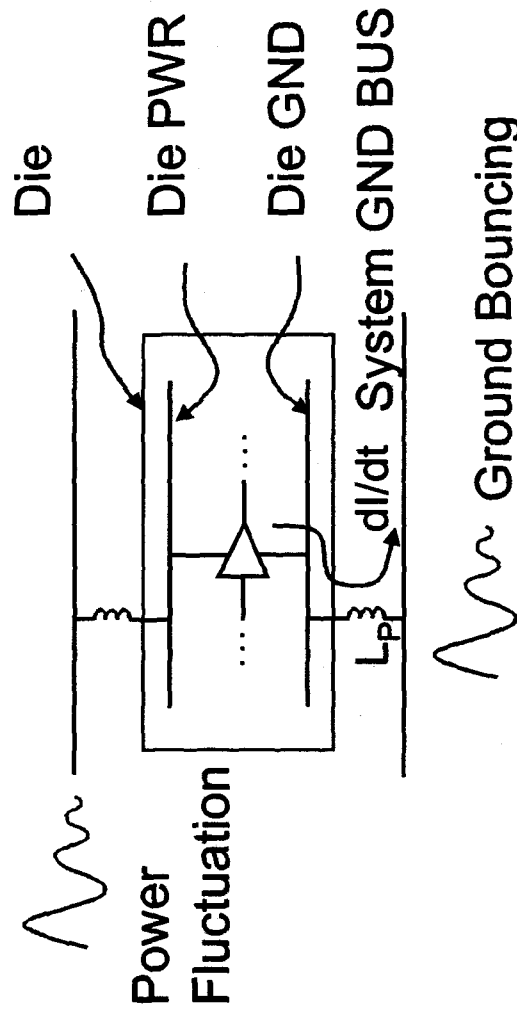


Semiconductor is a Function of Temperature.

At high temperature, semiconductor is meaningless

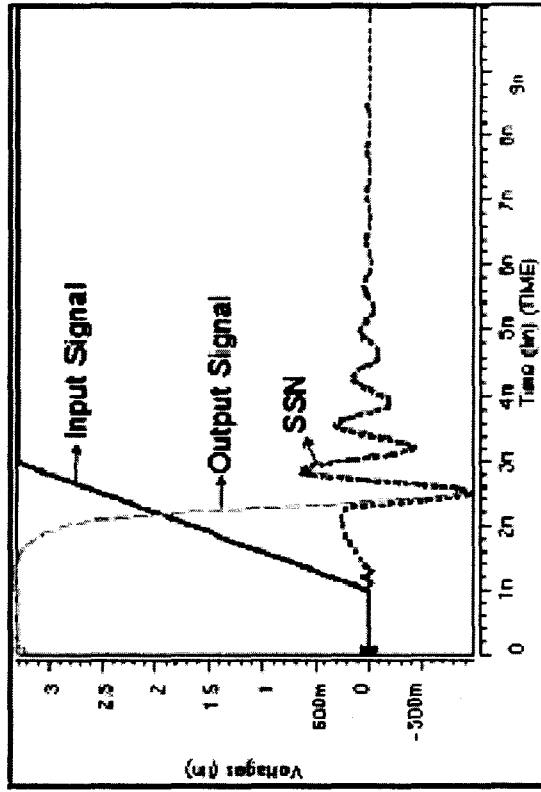
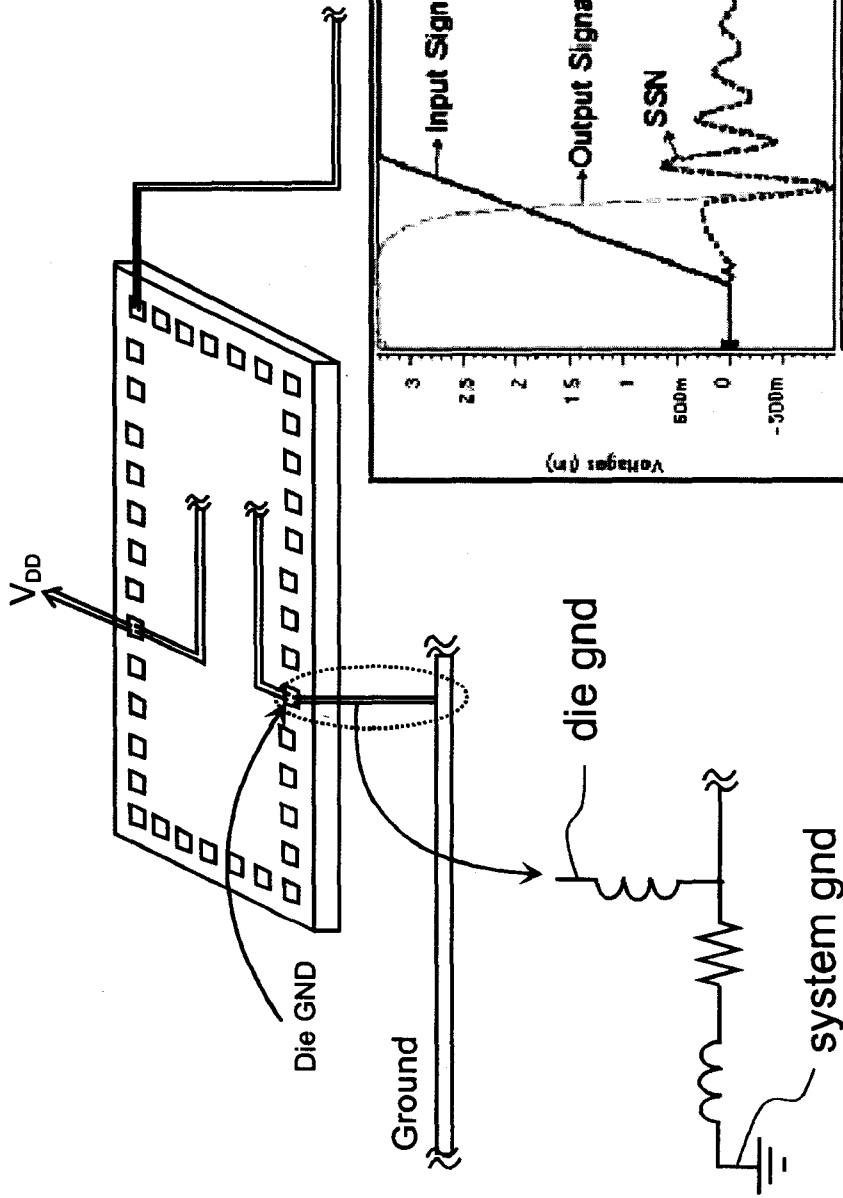
7. Simultaneous Switching Noise (Delta-I Noise)

⇒ Relative Ground and Power Definition Problem

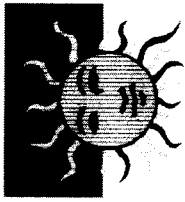


- Reference Potential Change
- Cause Glitch and Logic Failure
- Integrate Every Individual Noises

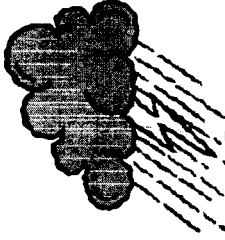
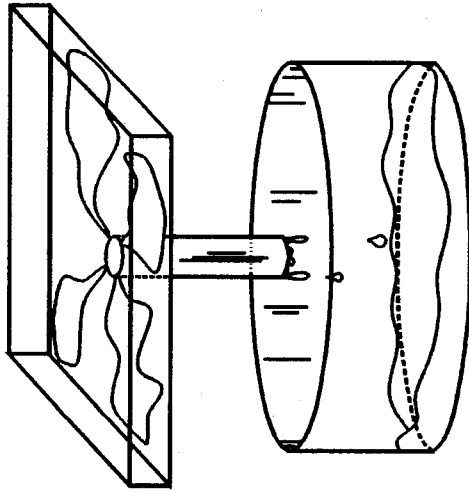
Simulation Example



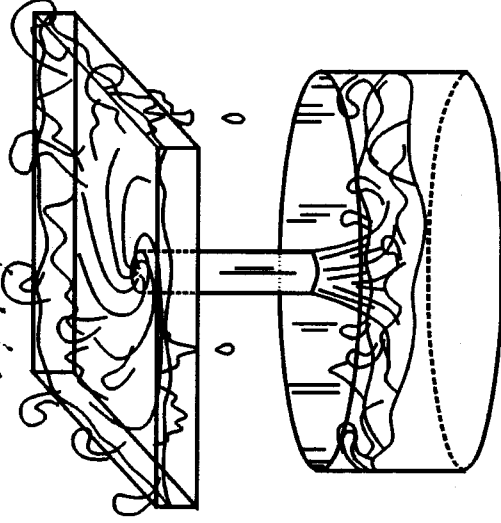
Another Point of View



Sunny Day

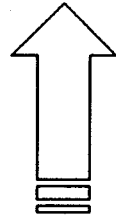


Rainy Day



Solution?

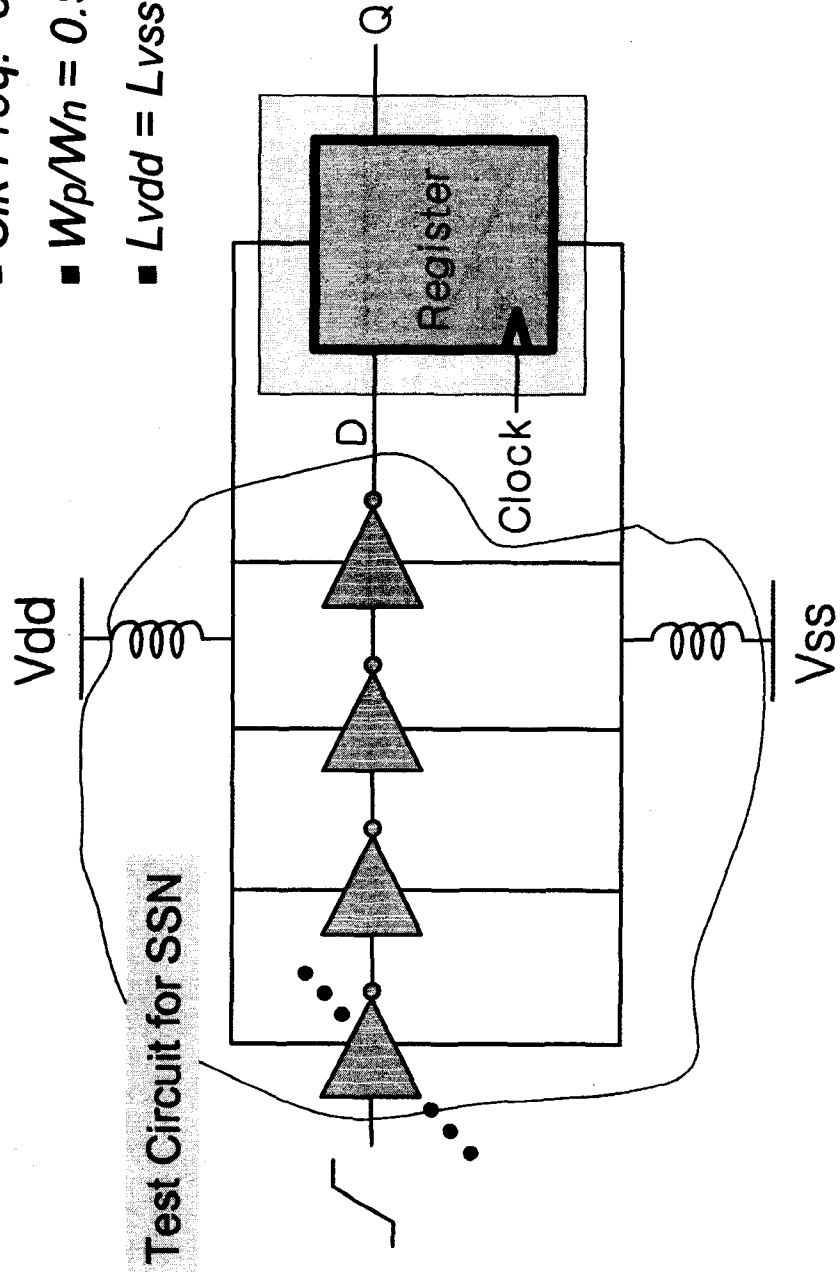
- Short
- Many Conduits
- 是 low water flowing



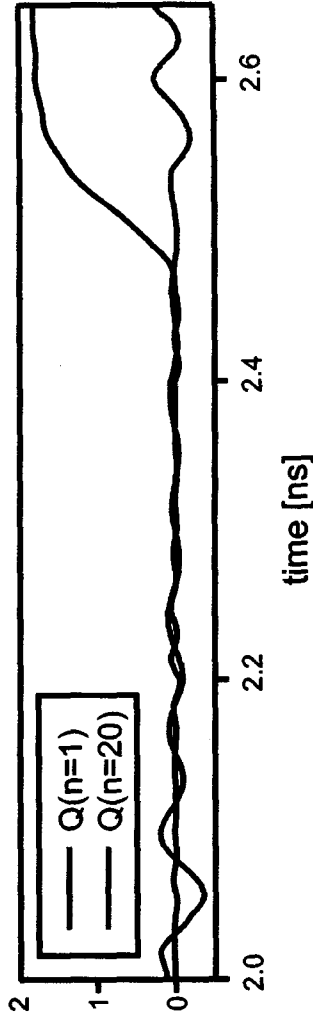
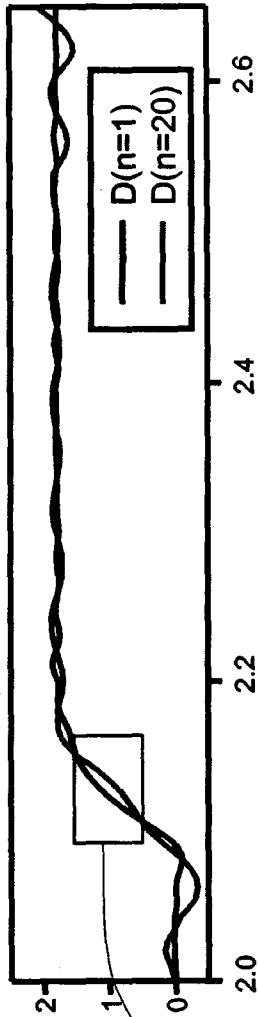
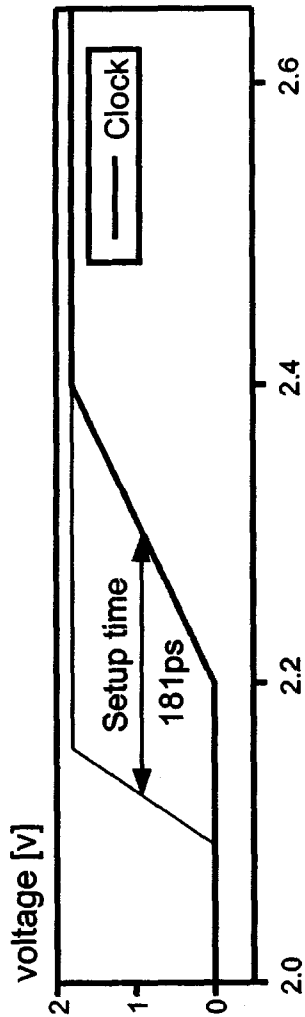
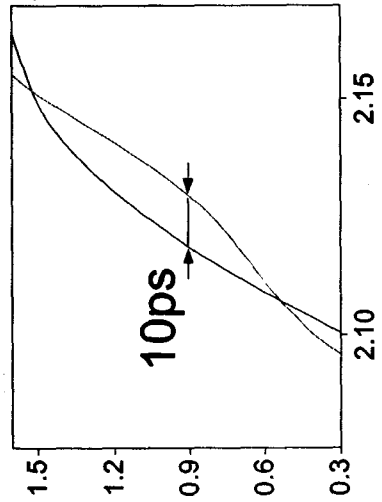
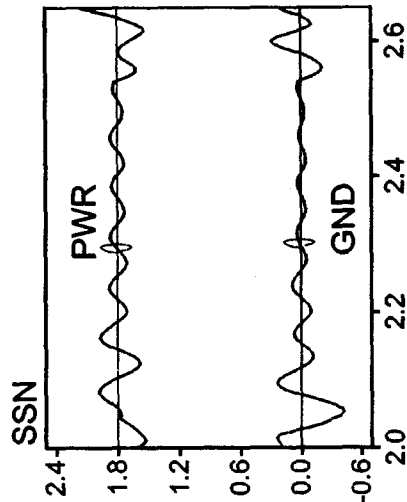
DIP --> BGA --> CSP
 Many I/O
 (X)

Example of a Circuit Failure due to SSN

- TSMC 0.18 μm /1.8V
- Clk Freq. = 500MHz
- $W_p/W_n = 0.9/0.36\mu\text{m}$
- $L_{vdd} = L_{vss} = 5\text{nH}$



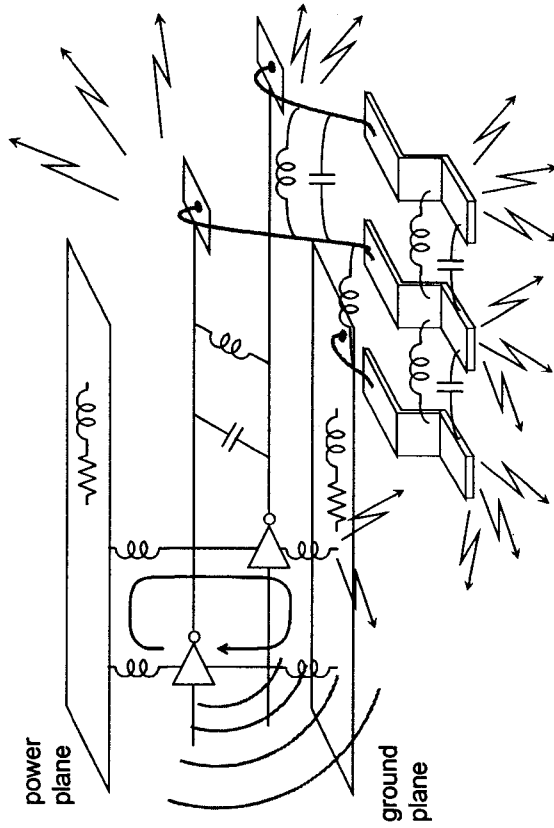
Simulation Result



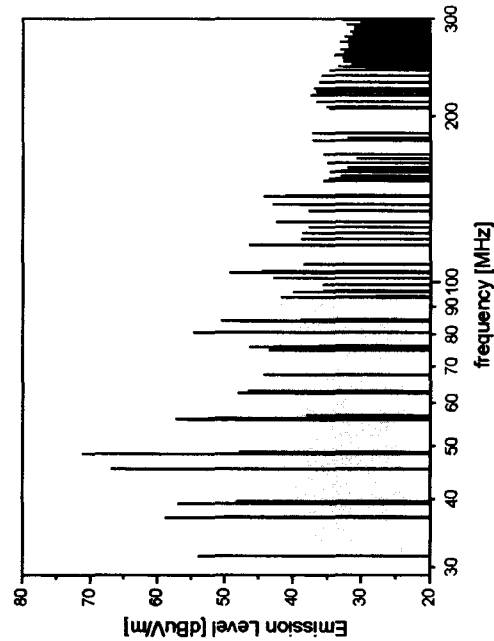
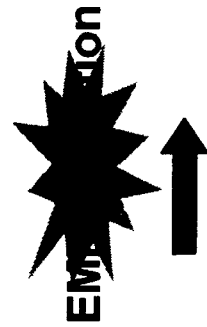
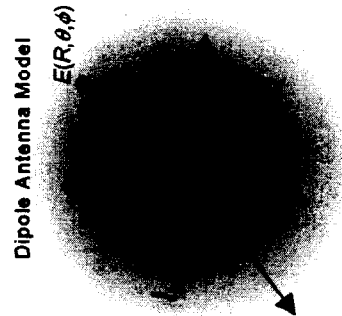
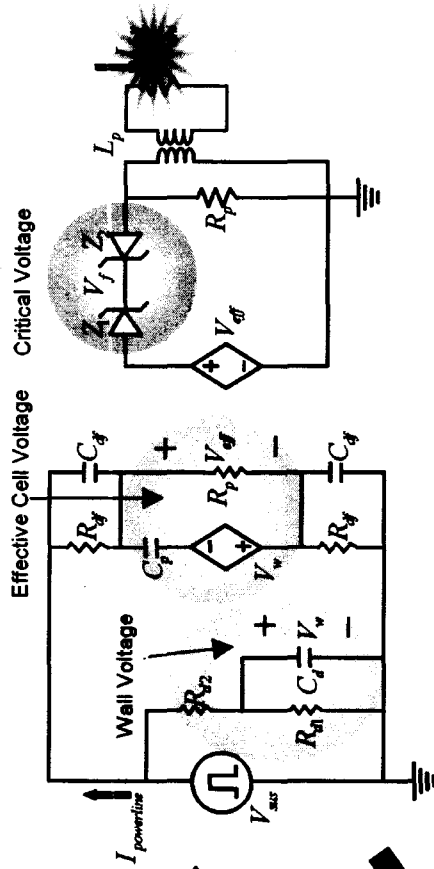
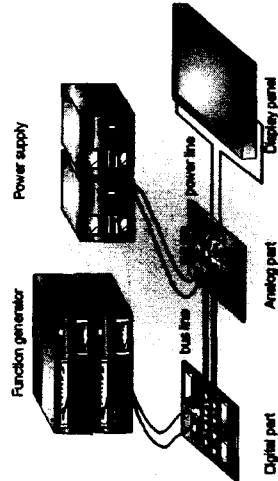
8. EMI/EMC of an Electronic System

- Why ?
 - Complicated System-Level Charge Dynamics (di/dt)
 - High-Speed and High-Density Digital Circuits

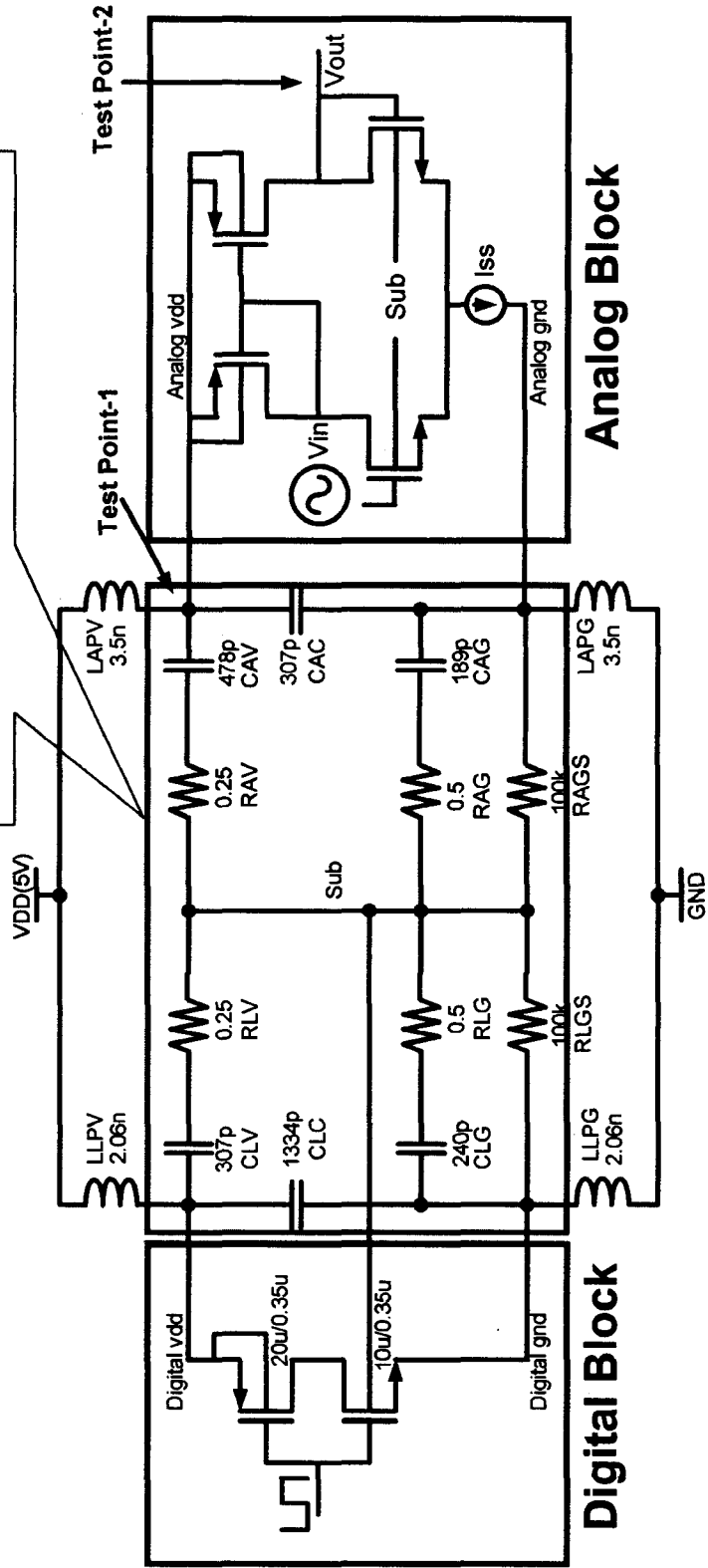
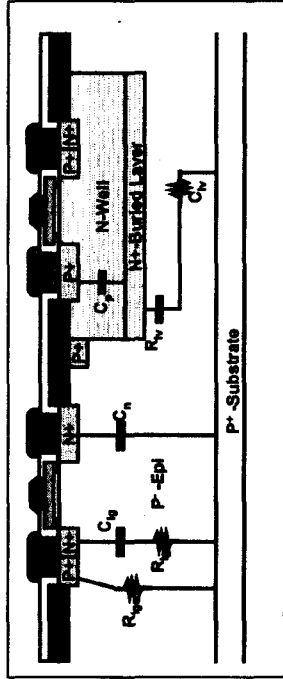
- Where ?
 - Clock Distribution Circuits
 - PCB Lines
 - IC Package
 - PWR&GND Distribution



Example of an EMI-Problem

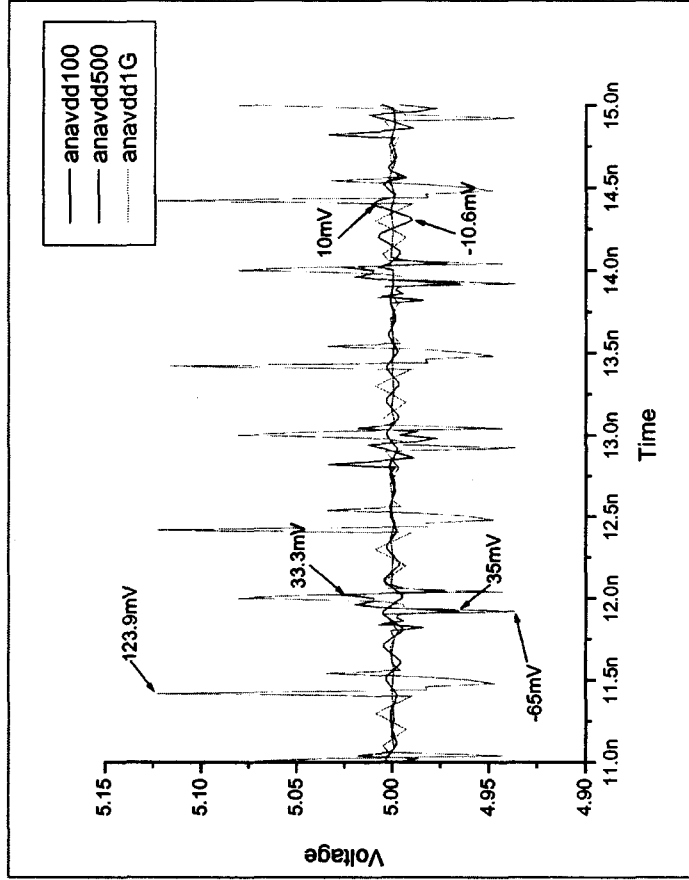
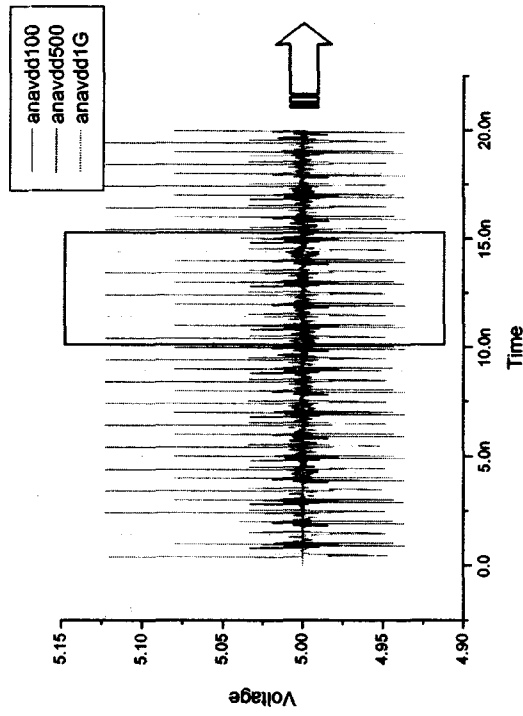


9. Silicon Substrate Problems

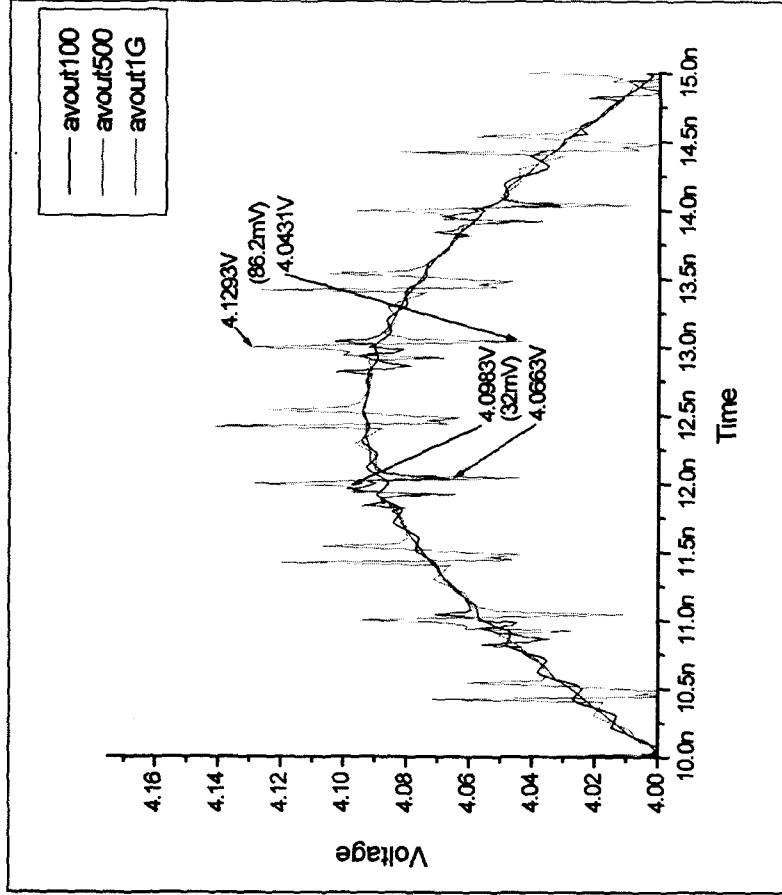
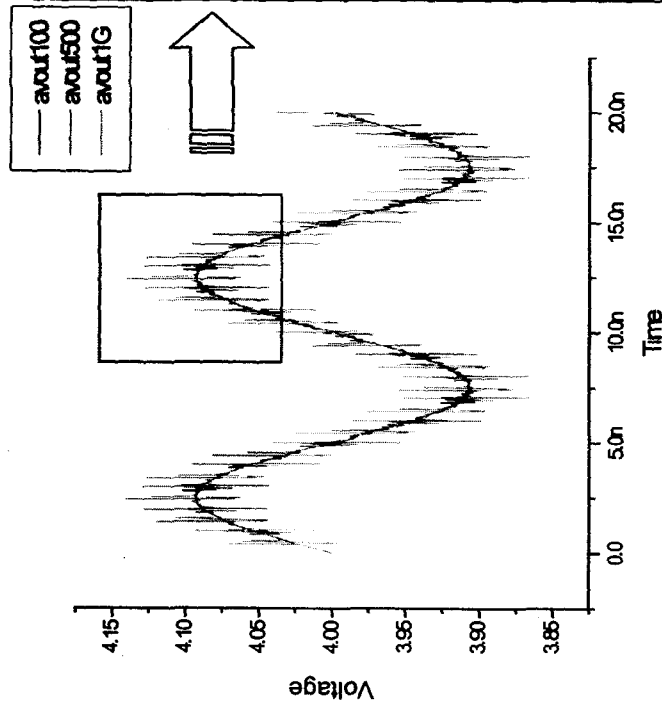


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Analog Power Line Noise (Test Point-1)



Output Noises (Test Point-2)



Noise Budgets

➔ **high integration / fine device / fast cycle time**

fast cycle time means high possibility of all the noise sources to be overlapped within narrow incident time window !!

Noise Budget

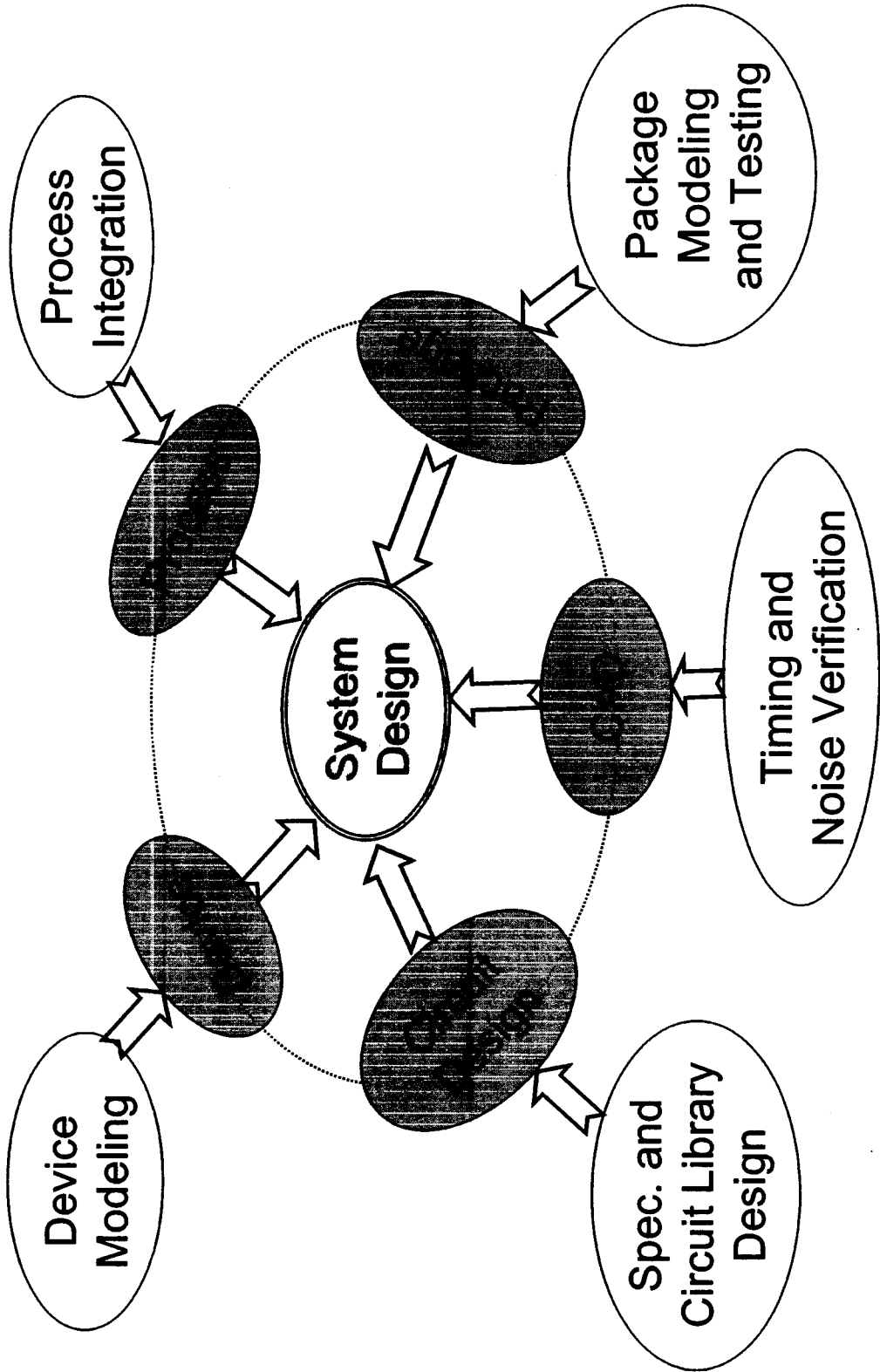
➔ **typical receiver circuit noise margin is about $\pm 35\%$ ~ $\pm 40\%$ of the total voltage swing.**

- X-talk uses $\pm 20\%$ ~ 25%
- Delta-I uses $\pm 5\%$
- Switching threshold voltage variation use about $\pm 3\%$
- Remaining $\pm 7\%$ is used for other noise sources

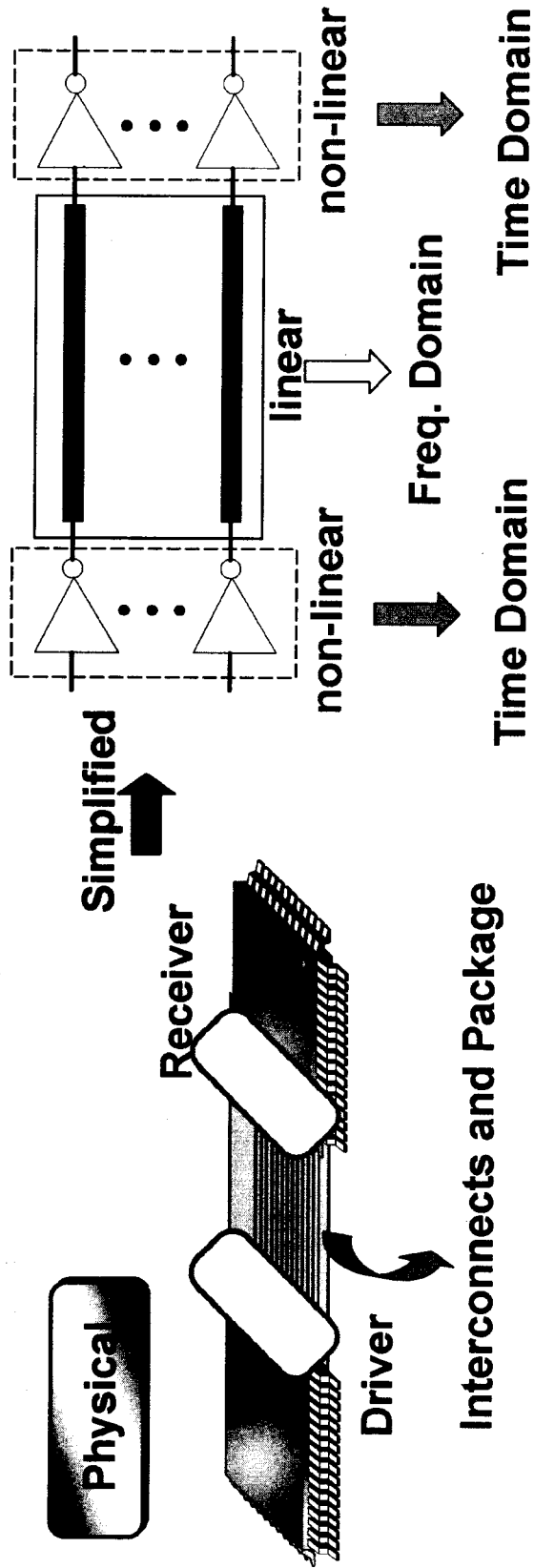
▲ **Estimation-Based Design ?**

How ??

Solutions for Future Technology Development



Generic Simulation Problem for Complicated Network



Conflict 1

Active & Components : Can be well described in Time Domain
 Interconnect & Package : Can be well described in Freq. Domain

➔ Domain – Transform ; Generic Conflict 1

- continued -

Conflict 2

Non-Linear Active Components

**Direct Analysis
(Numerical Analysis)**

**Approximation
(Linearization)**

Impractical

Inaccuracy



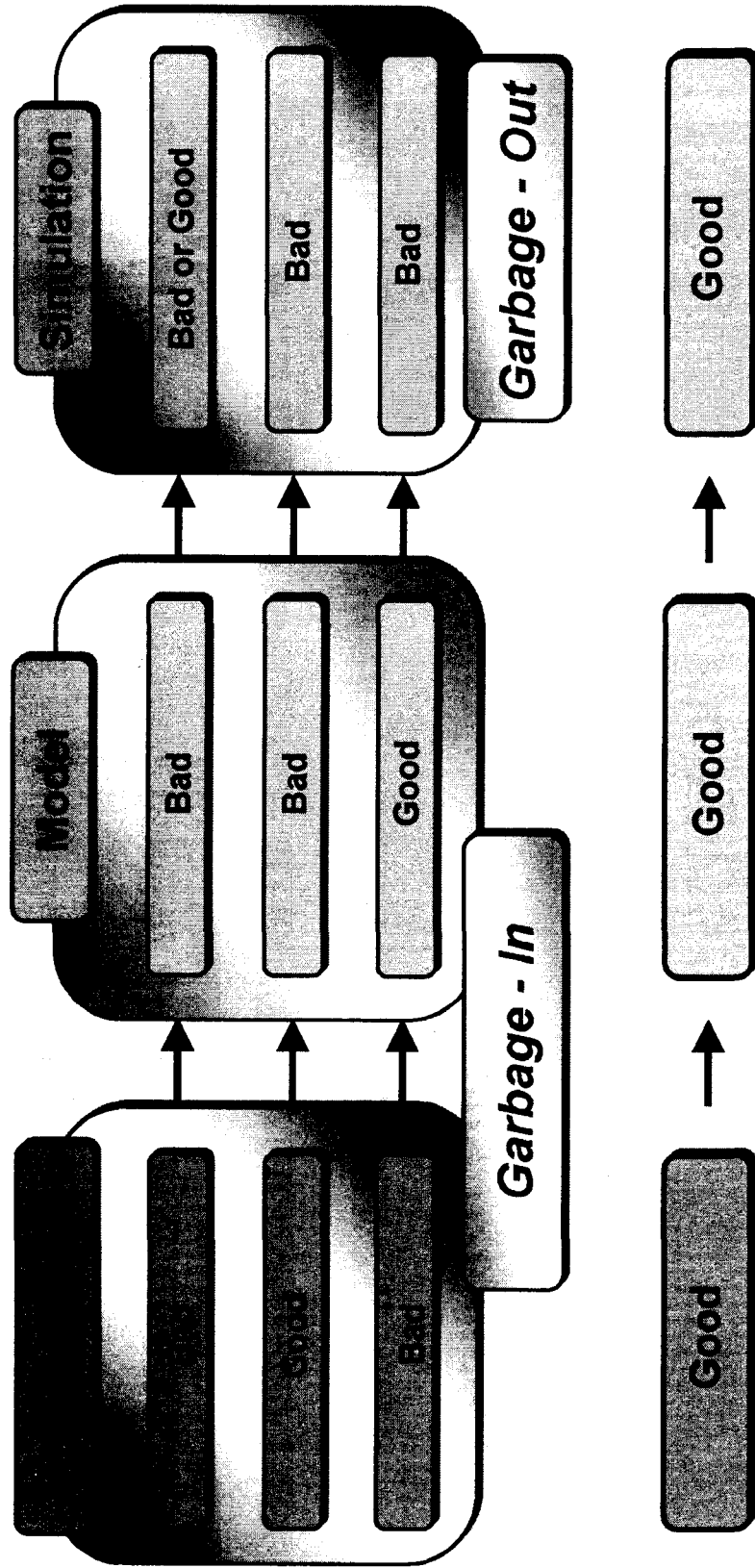
Generic Conflict 2

**Thus, W/O Domain Transform and W/ Approximation(Linearization)
but What are the Tolerable Boundaries?**

➔ Compromise (Trade – Off)

Conflict 3

Inherent Inaccuracy in Model, Parameters, & Simulation !!!



CAD TOOLS ?

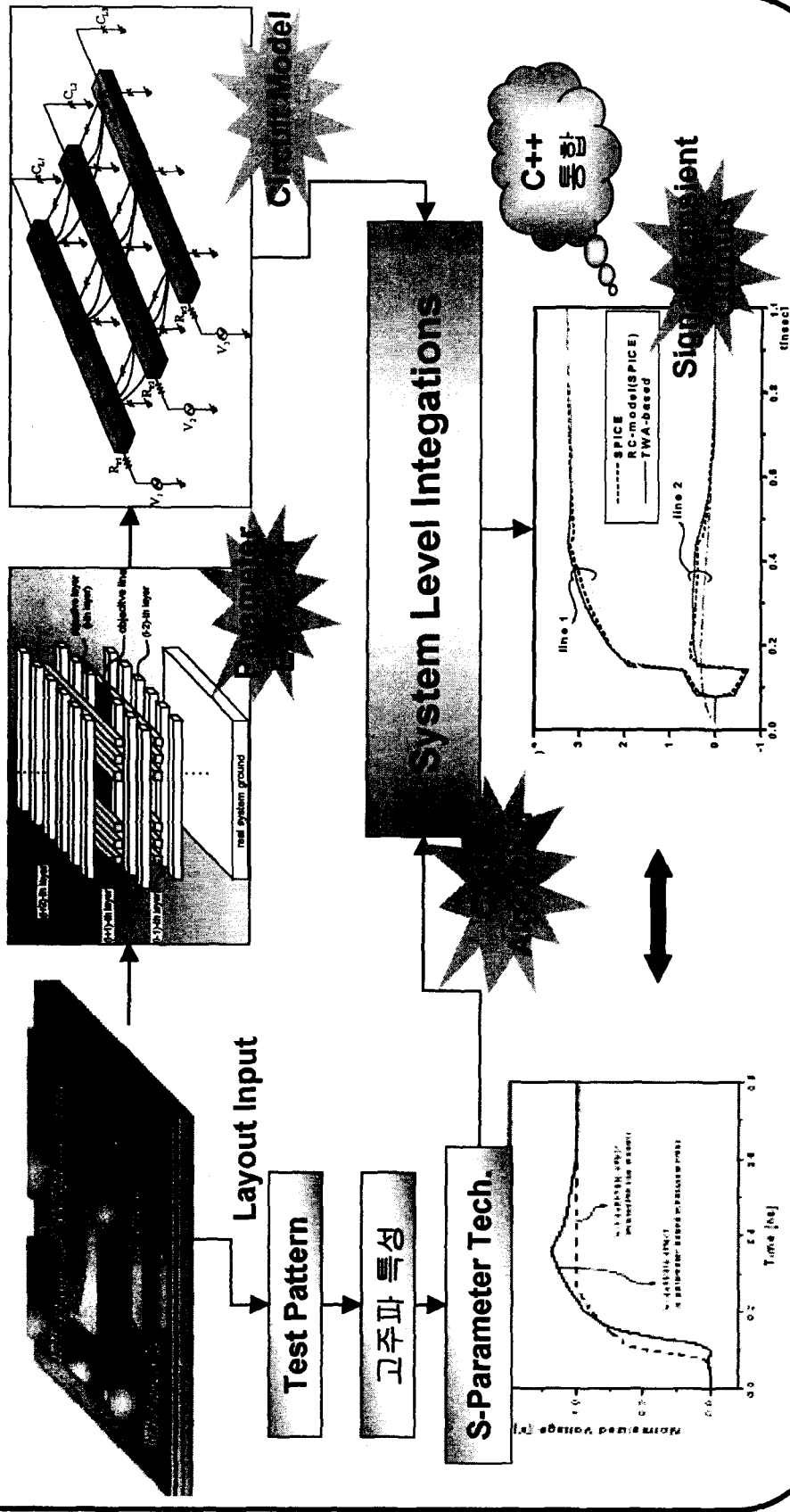
Still Do you believe the CAD Tools ?

- Masakazu Shoji -

- ***“The Present Design Automation” means “Low Performance”
Chip Design !!***
- ***“Circuit Simulation” is essentially a “Mechanical Procedure”
without Thinking !!***
- ***Why “Circuit Design Failures” occur ? Answer is Simple:
Because we don’t understand their working “Well Enough” !!***

Estimation-Based System Design

How to Estimate Signal Transients and Noises?



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Conclusion

**→ Future Circuit Design means
“Unimaginably Intricate Engineering Problems”**

Thus,

**Future Circuit Designers may be “Victims” of
“Inexorably Complicated Signal Integrity Problems”**